I INDICE COM A COM COME COM A COM A COM	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/726,677	CHOO ET AL.
Examiner	Art Unit
James A. Dudek	2871

	SEAR	CHED	
Class	Subclass	Date	Examiner
349	187,189, 190	4/26/2005	JAD
			<u> </u>
	_		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
		ļ	
		<del> </del>	
		<u> </u>	